

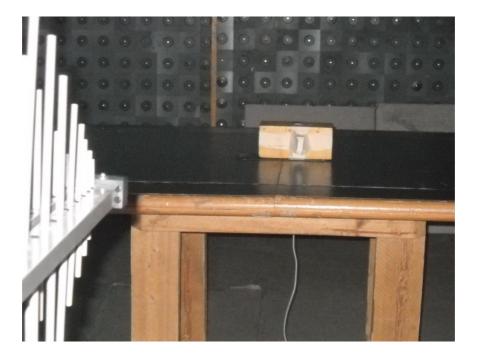
Photograph No.1 Setup for spurious emission field strength measurements in the anechoic chamber below 30 MHz





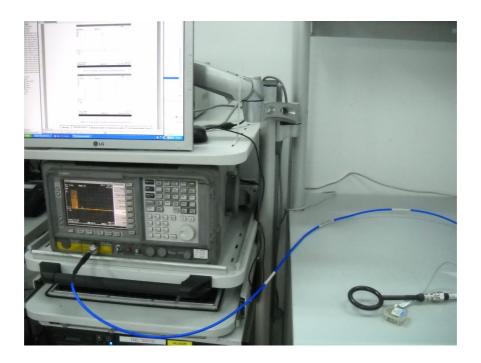
Photograph No.2 Setup for carrier field strength measurements at OATS

Photograph No.3 Setup for carrier field strength, OBW, spurious emission field strength measurements in the anechoic chamber in 30 – 1000 MHz range



Photograph No.4 Setup for spurious emission field strength measurements in the anechoic chamber above 1000 MHz





Photograph No.5 Setup for periodic operation measurements